



1/25/2008

RELIABILITY MONITOR REPORT
FOR

MFN Standard Metal Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DG201AESE+	DG211CSE	DG509AY	ICL7662CPA+	MAX1232CPA
MAX1232CPA+	MAX368CPN+			

The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 236608** **FITS: 0.5**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and

Process Information:

Process Description: MFN Standard Metal Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0545	DG211CSE	135C, 5.25V	1000 HRS	79	0	
HIGH TEMP OP LIFE	0550	MAX1232CPA	135C, 5.25V	1000 HRS	79	0	
HIGH TEMP OP LIFE	0604	ICL7662CPA+	135C, 5.25V	1000 HRS	77	0	
			135C, 5.25V	1000 HRS	77	0	
HIGH TEMP OP LIFE	0610	DG211CSE	135C, 5.25V	1000 HRS	77	0	
		DG509AY	135C, 5.25V	1000 HRS	77	0	
HIGH TEMP OP LIFE	0621	MAX368CPN+	135C, 5.25V	1000 HRS	45	0	
			135C, 5.25V	1000 HRS	45	0	
			135C, 5.25V	1000 HRS	45	0	
HIGH TEMP OP LIFE	0629	DG211CSE	135C, 5.25V	1000 HRS	80	0	
HIGH TEMP OP LIFE	0636	DG201AESE+	135C, 5.25V	1000 HRS	80	0	
HIGH TEMP OP LIFE	0641	DG211CSE	135C, 5.25V	1000 HRS	80	0	
HIGH TEMP OP LIFE	0644	MAX1232CPA	135C, 5.25V	1000 HRS	80	0	
HIGH TEMP OP LIFE	0648	DG211CSE	135C, 5.25V	1000 HRS	80	0	
HIGH TEMP OP LIFE	0706	MAX1232CPA+	135C, 5.25V	1000 HRS	80	0	
HIGH TEMP OP LIFE	0707	DG211CSE	135C, 5.25V	1000 HRS	60	0	
HIGH TEMP OP LIFE	0722	MAX1232CPA	135C, 5.25V	1000 HRS	80	0	
				Total:		0	

FAILURE RATE: **MTTF (YRS): 236608** **FITS: 0.5**